Search Notes



Application/Control No.
10/780,939
Examiner

Applicant(s)/Patent under Reexamination

LEE, CHANG-KYU

Art Unit

2617

SEARCHED			
Class	Subclass	Date	Examiner
455	9	6/26/2006	JDE
	13.3		
	26.1		
	63.4		
-	67.11		
	68		
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	115.1		
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	121		,
	123		
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	193.1		
	226.1		

INTERFERENCE SEARCHED			
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same as	above	6/27/2006	JDE
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Application/Control No.

10/780,939
Examiner

James D. Ewart

Applicant(s)/Patent under Reexamination

LEE, CHANG-KYU

Art Unit

2617

SEARCHED			
Class	Subclass	Date	Examiner
455	423	6/26/2006	JDE
	562.1		
	550.1		
	575.7		
343	703		
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	751		
	893		
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